

# SNUG Austin 2016 · Thursday, September 29, 2016 · Hilton Austin

8:00 – 8:45	Registration and Breakfast					
8:45 – 10:15	Welcome and Introduction: Jeff Montesano, SNUG Austin Tech Chair – Verilab Synopsys Keynote: "Innovation in the Age of Smart Everything" – Deirdre Hanford, Executive Vice President, Customer Engagement – Synopsys					
10:15 – 10:30	Break					
	Frontend Implementation	Backend Implementation	Digital Verification I	Digital Verification II	FPGA/Prototyping	Test
10:30 – 12:30	Improving Timing and Power with PrimeTime ECO Flows Synopsys	Best Practices for High-Performance, Energy-Efficient Implementations of the ARM® Cortex®-A73 Processor in 16-nm FinFET Plus (16FF+) Process Technology Using Synopsys Galaxy Design Platform ARM, Synopsys	Applying Stimulus and Sampling Outputs - UVM Verification Testing Techniques Sunburst Design	SystemVerilog: Reusable Class Features and Safe Initialization of Static Variables Advanced Micro Devices	Latch-Based CPU Prototyping with HAPS Platform	Synopsys Automotive Test Solution: Moving the DFT Needle Forward Synopsys
	Black-Boxing Techniques for Improving VC-LP Throughput Advanced Micro Devices	Floorplanning Large Blocks Using IC Compiler II Synopsys	Complex Constraints: Unleashing the Power of the VCS SystemVerilog Constraint Solver Samsung	Advanced X-Prop Usage for the NXP LS1080 Verification NXP Semiconductors, Synopsys	High-Level Performance Estimation on Virtual Prototypes Employing Timing Annotation ARM	
			Configuring a Date with a Model - A Guide to Configuration Objects and Register Models Verilab	Tough Bugs vs. Smart Tools - L2/L3 Cache Verification Using System Verilog, UVM, and Verdi Transaction Debugging Centaur Technology, Synopsys	Accelerate Your Prototyping Productivity Leveraging HAPS Integrated Prototyping Solution Synopsys	
12:30 – 1:30	Lunch					
	Frontend Implementation	Backend Implementation	Digital Verification I	Digital Verification II	Full Custom Implementation	Test
1:30 – 3:00	Design Compiler Update and Runtime Best Practices Synopsys	Best Practices for a Performance- and Area-Focused Implementation of High-Performance GPUs Using Galaxy Design Platform Synopsys	Unique Methodology to Streamline the Checking of Design Tie-Offs NXP Semiconductors, Synopsys	Molding Functional Coverage and Reporting for Highly Configurable IP Broadcom	Statistical Characterization Methodology to Design and Margin for 16nm FinFET Flops NXP Semiconductors	DFTMAX Ultra User Experience for Small, Digital, Mixed-Signal Devices Maxim Integrated
	Effective Reporting and Analysis of Timing Results with PrimeTime Synopsys	Updates and Best Practices for IC Compiler II with In-Design IC Validator Synopsys	Essential Ingredients of Formal Based Verification Synopsys	Effective SystemVerilog Functional Coverage: Design and Coding Recommendations Verilab	Power-Intent Verification Methodology in Multi-Voltage Domain Custom Memory Macro to Prevent Circuit Failures Advanced Micro Devices, Synopsys	DFTMAX Ultra: Achieve Additional Cost Reduction with Hardware-Assisted Shift Power Reduction Synopsys
						Low-Power DFT and Effective Test Pattern Count Reduction in a Custom High-Performance Applications Processor Design Samsung, Synopsys
3:00 – 3:15	Break					
3:15 – 5:15	ECO User Case Studies Using Formality Ultra Synopsys	Achieving Correlation Between Synthesis and Routed Design for High-Performance Block Advanced Micro Devices	Verifying Microprocessor Debug-Bus Connectivity Formally Using VC Formal Advanced Micro Devices	Leveraging LevelDB for Unit-Level Replay of Top-Level Stimulus in UVM Samsung	Custom Compiler Technology Walkthrough Synopsys	TetraMAX II: Reduce Test Cost by 25 Percent with 10X Faster Runtime Synopsys
		Structural MSCTS Implementation Best Practices Advanced Micro Devices	Using Formal Tools to Verify Datapath Designs During Various Phases of a Processor Development Advanced Micro Devices, Oski Technology	Layered Testbench Architecture for Serial Protocol Using UVM einfochips, Synopsys	Walk-Through of SAE: The New Simulation Analysis Environment in the Latest Release of HSPICE, FineSim, and CustomSim Synopsys	TetraMAX II ATPG, Broadcom's Results and Experience Synopsys, Broadcom
	Static Analysis with SpyGlass Synopsys	Implementing a 150M+ instance Networking chip @28nm with Galaxy Platform Synopsys	The Lights in the Tunnel: Coverage Analysis for Formal Verification Oracle, Synopsys	Advanced Verification Techniques for the NXP LS1080 Memory Validation NXP Semiconductors, Synopsys		Connectivity Validation with SpyGlass Synopsys
5:15 – 6:30	Awards and Evening Event					